







SN74HCS02

ZHCSKW3B - DECEMBER 2019 - REVISED JANUARY 2021

# SN74HCS02 具有施密特触发输入的四路双输入或非门

### 1 特性

- 宽工作电压范围: 2V 至 6V
- 施密特触发输入可实现慢速或高噪声输入信号
- 低功耗
  - I<sub>CC</sub> 典型值为 100nA
  - 输入泄漏电流典型值为 ±100nA
- 电压为 6V 时,输出驱动为 ±7.8mA
- 工作环境温度范围: 40°C 至 +125°C, TA

### 2 应用

- 警报/篡改检测电路
- S-R 锁存器

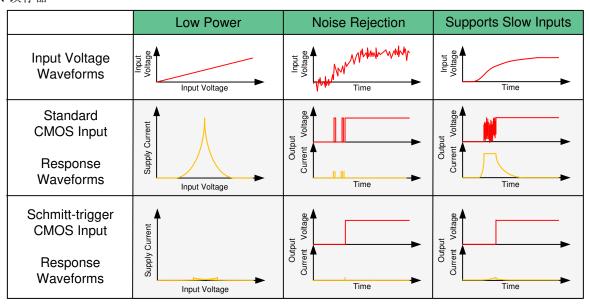
### 3 说明

此器件包含四个具有施密特触发输入的独立双输入或非 门。每个逻辑门以正逻辑执行布尔函数  $Y = \overline{A + B}$ 。

#### 器件信息

	AA )   1A -C-							
器件型号	封装 <sup>(1)</sup>	封装尺寸(标称值)						
SN74HCS02PW	5.00mm × 4.40mm							
SN74HCS02D	74HCS02D SOIC (14)							
SN74HCS02BQA	WQFN (14)	3.00mm x 2.50mm						

如需了解所有可用封装,请参阅数据表末尾的可订购产品附 录。



施密特触发输入的优势



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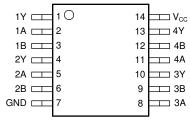
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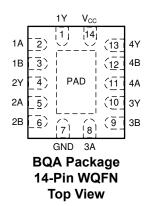
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# **5 Pin Configuration and Functions**



D or PW Package 14-Pin SOIC or TSSOP Top View



#### **Pin Functions**

	PIN I/O		DESCRIPTION				
NAME NO.		_ 1/0	DESCRIPTION				
1Y	1	Output	Channel 1, Output Y				
1A	2	Input	Channel 1, Input A				
1B	3	Input	Channel 1, Input B				
2Y	4	Output	Channel 2, Output Y				
2A	5	Input	Channel 2, Input A				
2B	6	Input	Channel 2, Input B				
GND	7	_	Ground				
3A	8	Input	Channel 3, Input A				
3B	9	Input	Channel 3, Input B				
3Y	10	Output	Channel 3, Output Y				
4A	11	Input	Channel 4, Input A				
4B	12	Input	Channel 4, Input B				
4Y	13	Output	Channel 4, Output Y				
V <sub>CC</sub>	14	_	Positive Supply				
Thermal Pad	(1)	_	The thermal pad can be connected to GND or left floating. Do not connect to any other signal or supply				

### 1. BQA Package only.

### **6 Specifications**

### **6.1 Absolute Maximum Ratings**

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		- 0.5	7	V
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>	$V_1 < -0.5 \text{ or } V_1 > V_{CC} + 0.5$		±20	mA
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	$V_{O} < -0.5 \text{ or } V_{O} > V_{CC} + 0.5$		±20	mA
Io	Continuous output current	V <sub>O</sub> = 0 to V <sub>CC</sub>		±35	mA
	Continuous current through V <sub>CC</sub> or GND			±70	mA
TJ	Junction temperature <sup>(3)</sup>			150	°C
T <sub>stg</sub>	Storage temperature		- 65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 6.2 ESD Ratings

			VALUE	UNIT
V	V <sub>(ESD)</sub> Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/ JEDEC JS-001 <sup>(1)</sup>	±4000	V
V <sub>(ESD)</sub>	Liectrostatic discriarge	Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>	±1500	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

### **6.3 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V <sub>CC</sub>	Supply voltage	2	6	V
VI	Input voltage	0	V <sub>CC</sub>	V
Vo	Output voltage	0	V <sub>CC</sub>	V
∆ t/ ∆ v	Input transition rise and fall rate		Unlimited	ns/V
T <sub>A</sub>	Ambient temperature	- 40	125	°C

Product Folder Links: SN74HCS02

<sup>(2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed. Do not exceed the absolute maximum voltage supply rating.

<sup>(3)</sup> Guaranteed by design.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### **6.4 Thermal Information**

	THERMAL METRIC(1)	PW (TSSOP)	D (SOIC)	BQA (WQFN)	UNIT
		14 PINS	14 PINS	14 PINS	
R <sub>0</sub> JA	Junction-to-ambient thermal resistance	151.7	133.6	109.7	°C/W
R <sub>0</sub> JC(top)	Junction-to-case (top) thermal resistance	79.4	89.0	111.0	°C/W
R <sub>0</sub> JB	Junction-to-board thermal resistance	94.7	89.5	77.9	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	25.2	45.5	20.2	°C/W
ΨЈВ	Junction-to-board characterization parameter	94.1	89.1	77.8	°C/W
R <sub>θ</sub> JC(bot)	Junction-to-case (bottom) thermal resistance	N/A	N/A	56.6	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

### **6.5 Electrical Characteristics**

over operating free-air temperature range; typical ratings measured at  $T_A = 25$ °C (unless otherwise noted).

	PARAMETER	TEST CO	NDITIONS	V <sub>CC</sub>	MIN	TYP	MAX	UNIT
				2 V	0.7		1.5	
$V_{T+}$	V <sub>T+</sub> Positive switching threshold			4.5 V	1.7		3.15	V
				6 V	2.1		4.2	
				2 V	0.3		1.0	
$V_{T-}$	Negative switching threshold			4.5 V	0.9		2.2	V
				6 V	1.2		3.0	
				2 V	0.2		1.0	
$\Delta V_T$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )			4.5 V	0.4		1.4	V
				6 V	0.6		1.6	
			I <sub>OH</sub> = -20 μA	2 V to 6 V	V <sub>CC</sub> - 0.1	V <sub>CC</sub> - 0.002		
$V_{OH}$	High-level output voltage	$V_I = V_{IH}$ or $V_{IL}$	I <sub>OH</sub> = -6 mA	4.5 V	4.0	4.3		V
			I <sub>OH</sub> = -7.8 mA	6 V	5.4	5.75		
			I <sub>OL</sub> = 20 μA	2 V to 6 V		0.002	0.1	
$V_{OL}$	Low-level output voltage	$V_I = V_{IH}$ or $V_{IL}$	I <sub>OL</sub> = 6 mA	4.5 V		0.18	0.30	V
			I <sub>OL</sub> = 7.8 mA	6 V		0.22	0.33	
I <sub>I</sub>	Input leakage current	$V_I = V_{CC}$ or 0		6 V		±100	±1000	nA
I <sub>CC</sub>	Supply current	$V_I = V_{CC}$ or 0, $I_C$	<sub>D</sub> = 0	6 V		0.1	2	μA
Ci	Input capacitance			2 V to 6 V			5	pF
C <sub>pd</sub>	Power dissipation capacitance per gate	No load		2 V to 6 V		10		pF

### 6.6 Switching Characteristics

over operating free-air temperature range; typical ratings measured at  $T_A = 25$ °C (unless otherwise noted). See Parameter Measurement Information.

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub>	MIN	TYP	MAX	UNIT
	t <sub>pd</sub> Propagation delay			2 V		16	36	
t <sub>pd</sub>		A or B		4.5 V		7	13	ns
				6 V		6	12	
			Υ	2 V		7.7	13	
t <sub>t</sub> Transition	Transition-time			4.5 V		4	6.1	ns
				6 V		3.5	5.1	

### **6.7 Typical Characteristics**

 $T_A = 25^{\circ}C$ 

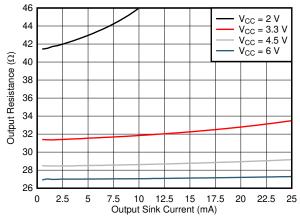


图 6-1. Output driver resistance in LOW state.

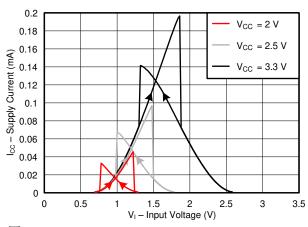


图 6-3. Supply current across input voltage, 2-, 2.5-, and 3.3-V supply

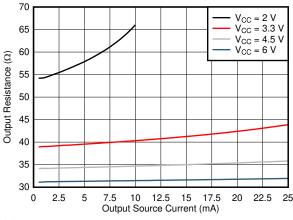


图 6-2. Output driver resistance in HIGH state.

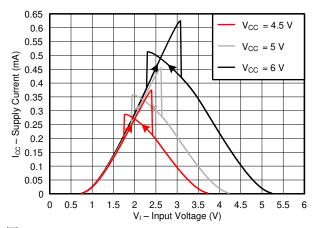


图 6-4. Supply current across input voltage, 4.5-, 5-, and 6-V supply

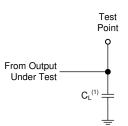


### 7 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_t$  < 2.5 ns.

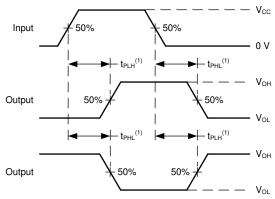
For clock inputs,  $f_{\text{max}}$  is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



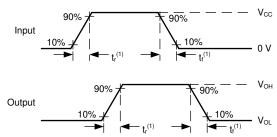
(1) C<sub>L</sub> includes probe and test-fixture capacitance.

### 图 7-1. Load Circuit for Push-Pull Outputs



(1) The greater between  $t_{PLH}$  and  $t_{PHL}$  is the same as  $t_{pd}$ .

图 7-2. Voltage Waveforms Propagation Delays



(1) The greater between  $t_{\text{r}}$  and  $t_{\text{f}}$  is the same as  $t_{\text{t}}$ .

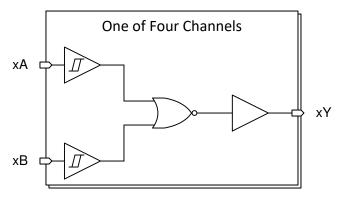
图 7-3. Voltage Waveforms, Input and Output Transition Times

### 8 Detailed Description

#### 8.1 Overview

This device contains four independent 2-input NOR Gates with Schmitt-trigger inputs. Each gate performs the Boolean function  $Y = \overline{A + B}$  in positive logic.

### 8.2 Functional Block Diagram



#### 8.3 Feature Description

#### 8.3.1 Balanced CMOS Push-Pull Outputs

This device includes balanced CMOS push-pull outputs. The term "balanced" indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

Unused push-pull CMOS outputs should be left disconnected.

### 8.3.2 CMOS Schmitt-Trigger Inputs

This device includes inputs with the Schmitt-trigger architecture. These inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics* table from the input to ground. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings* table, and the maximum input leakage current, given in the *Electrical Characteristics* table, using Ohm's law ( $R = V \div I$ ).

The Schmitt-trigger input architecture provides hysteresis as defined by  $\Delta V_T$  in the *Electrical Characteristics* table, which makes this device extremely tolerant to slow or noisy inputs. While the inputs can be driven much slower than standard CMOS inputs, it is still recommended to properly terminate unused inputs. Driving the inputs with slow transitioning signals will increase dynamic current consumption of the device. For additional information regarding Schmitt-trigger inputs, please see Understanding Schmitt Triggers.

#### 8.3.3 Clamp Diode Structure

The inputs and outputs to this device have both positive and negative clamping diodes as depicted in Electrical Placement of Clamping Diodes for Each Input and Output.

### **CAUTION**

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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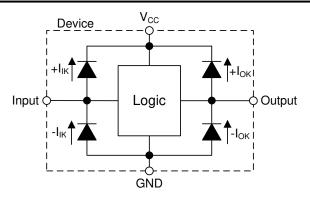


图 8-1. Electrical Placement of Clamping Diodes for Each Input and Output

### 8.4 Device Functional Modes

Function Table lists the functional modes of the SN74HCS02.

表 8-1. Function Table

INPU	TS <sup>(1)</sup>	OUTPUT
Α	В	Y
L	L	Н
Н	Х	L
X	н	L

(1) H = High Voltage Level, L = Low Voltage Level, X = Don't

### 9 Application and Implementation

#### 备注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

#### 9.1 Application Information

In this application, two 2-input NOR gates are used to create an SR latch as shown in 

9-1. The two additional gates can be used for a second SR latch, or the inputs can be grounded and both channels left unused.

The SN74HCS02 is used to drive the tamper indicator LED and provide one bit of data to the system controller. When the tamper switch outputs HIGH, the output Q becomes HIGH. This output remains HIGH until the system controller addresses the event and sends a HIGH signal to the R input which returns the Q output back to LOW.

The user can add a small RC to the feedback path of the NOR gates to default the output to a certain state, which can create slow transition rates. This fact makes the SN74HCS02 ideal for the application because it has Schmitt-trigger inputs that do not have input transition rate requirements.

### 9.2 Typical Application

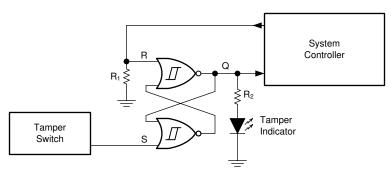


图 9-1. Typical application block diagram

#### 9.2.1 Design Requirements

#### 9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics*.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74HCS02 plus the maximum static supply current,  $I_{CC}$ , listed in *Electrical Characteristics* and any transient current required for switching. The logic device can only source as much current as is provided by the positive supply source. Be sure not to exceed the maximum total current through  $V_{CC}$  listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN74HCS02 plus the maximum supply current,  $I_{CC}$ , listed in *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current as can be sunk into its ground connection. Be sure not to exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.

The SN74HCS02 can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the datasheet specifications. Larger capacitive loads can be applied, however it is not recommended to exceed 50 pF.

The SN74HCS02 can drive a load with total resistance described by  $R_L \geqslant V_O$  /  $I_O$ , with the output voltage and current defined in the *Electrical Characteristics* table with  $V_{OH}$  and  $V_{OL}$ . When outputting in the high state, the

Product Folder Links: SN74HCS02

output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the  $V_{CC}$  pin.

Total power consumption can be calculated using the information provided in CMOS Power Consumption and Cpd Calculation.

Thermal increase can be calculated using the information provided in Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices.

#### **CAUTION**

The maximum junction temperature,  $T_{J(max)}$  listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

#### 9.2.1.2 Input Considerations

Input signals must cross  $V_{t-(min)}$  to be considered a logic LOW, and  $V_{t+(max)}$  to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either  $V_{CC}$  or ground. These can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input is to be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The resistor size is limited by drive current of the controller, leakage current into the SN74HCS02, as specified in the *Electrical Characteristics*, and the desired input transition rate. A 10-k  $\Omega$  resistor value is often used due to these factors.

The SN74HCS02 has no input signal transition rate requirements because it has Schmitt-trigger inputs.

Another benefit to having Schmitt-trigger inputs is the ability to reject noise. Noise with a large enough amplitude can still cause issues. To know how much noise is too much, please refer to the  $\Delta V_{T(min)}$  in the *Electrical Characteristics*. This hysteresis value will provide the peak-to-peak limit.

Unlike what happens with standard CMOS inputs, Schmitt-trigger inputs can be held at any valid value without causing huge increases in power consumption. The typical additional current caused by holding an input at a value other than V<sub>CC</sub> or ground is plotted in the *Typical Characteristics*.

Refer to the Feature Description section for additional information regarding the inputs for this device.

#### 9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to  $V_{\text{CC}}$  or ground.

Refer to Feature Description section for additional information regarding the outputs for this device.

#### 9.2.2 Detailed Design Procedure

Add a decoupling capacitor from V<sub>CC</sub> to GND. The capacitor needs to be placed physically close to the
device and electrically close to both the V<sub>CC</sub> and GND pins. An example layout is shown in the Layout
section.

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- 2. Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit, however it will ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the SN74HCS02 to the receiving device(s).
- 3. Ensure the resistive load at the output is larger than  $(V_{CC} / I_{O(max)})$   $\Omega$ . This will ensure that the maximum output current from the *Absolute Maximum Ratings* is not violated. Most CMOS inputs have a resistive load measured in megaohms; much larger than the minimum calculated above.
- 4. Thermal issues are rarely a concern for logic gates, however the power consumption and thermal increase can be calculated using the steps provided in the application report, CMOS Power Consumption and Cpd Calculation.

### 9.2.3 Application Curves

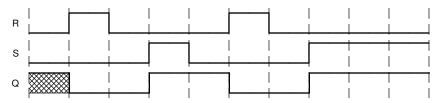


图 9-2. Application timing diagram

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### 10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1-  $\mu$  F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1-  $\mu$  F and 1-  $\mu$  F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in given example layout image.

### 11 Layout

#### 11.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V<sub>CC</sub>, whichever makes more sense for the logic function or is more convenient.

### 11.2 Layout Example

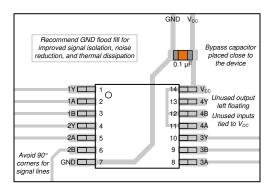


图 11-1. Example layout for the SN74HCS02



### 12 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

### **12.1 Documentation Support**

#### 12.1.1 Related Documentation

For related documentation see the following:

- Texas Instruments, HCMOS Design Considerations application report (SCLA007)
- Texas Instruments, CMOS Power Consumption and Cpd Calculation application report (SDYA009)
- Texas Instruments, Designing With Logic application report

#### 12.2 接收文档更新通知

要接收文档更新通知,请导航至 ti.com 上的器件产品文件夹。点击*订阅更新* 进行注册,即可每周接收产品信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

#### 12.3 支持资源

TI E2E™ 支持论坛是工程师的重要参考资料,可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

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#### 12.4 Trademarks

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#### 12.5 静电放电警告



静电放电 (ESD) 会损坏这个集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理和安装程序,可能会损坏集成电路。

ESD 的损坏小至导致微小的性能降级,大至整个器件故障。精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

### 12.6 术语表

TI术语表本术语表列出并解释了术语、首字母缩略词和定义。



### 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking
	(1)	(2)			(3)	(4)	(5)		(6)
SN74HCS02BQAR	Active	Production	WQFN (BQA)   14	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS02
SN74HCS02BQAR.A	Active	Production	WQFN (BQA)   14	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS02
SN74HCS02BQARG4	Active	Production	WQFN (BQA)   14	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS02
SN74HCS02BQARG4.A	Active	Production	WQFN (BQA)   14	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS02
SN74HCS02DR	Active	Production	SOIC (D)   14	2500   LARGE T&R	Yes	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 125	HCS02
SN74HCS02DR.A	Active	Production	SOIC (D)   14	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS02
SN74HCS02PWR	Active	Production	TSSOP (PW)   14	2000   LARGE T&R	Yes	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 125	HCS02
SN74HCS02PWR.A	Active	Production	TSSOP (PW)   14	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS02

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

## PACKAGE OPTION ADDENDUM

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN74HCS02:

• Automotive : SN74HCS02-Q1

NOTE: Qualified Version Definitions:

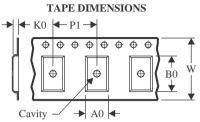
• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

# **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

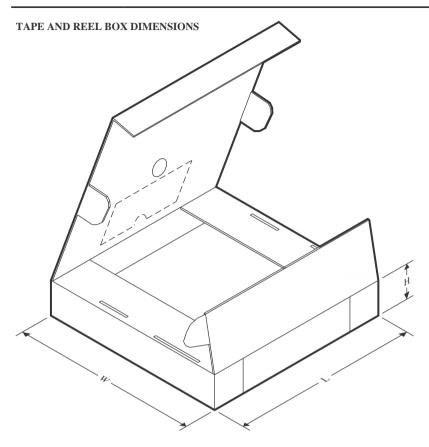


#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HCS02BQAR	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1
SN74HCS02BQARG4	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1
SN74HCS02DR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
SN74HCS02PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 23-Jul-2025



#### \*All dimensions are nominal

7 III danierie dre riemana										
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)			
SN74HCS02BQAR	WQFN	BQA	14	3000	210.0	185.0	35.0			
SN74HCS02BQARG4	WQFN	BQA	14	3000	210.0	185.0	35.0			
SN74HCS02DR	SOIC	D	14	2500	353.0	353.0	32.0			
SN74HCS02PWR	TSSOP	PW	14	2000	356.0	356.0	35.0			



SMALL OUTLINE PACKAGE



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



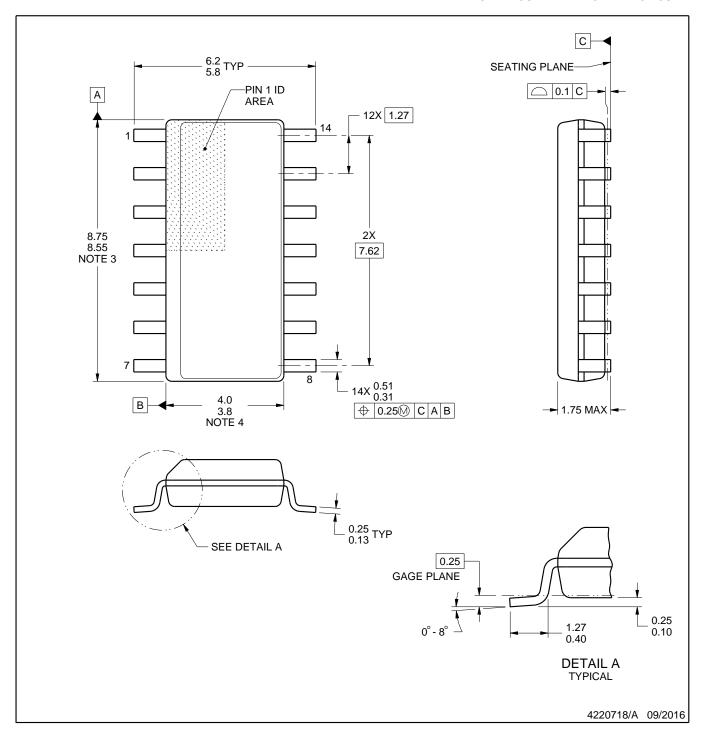
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE INTEGRATED CIRCUIT



#### NOTES:

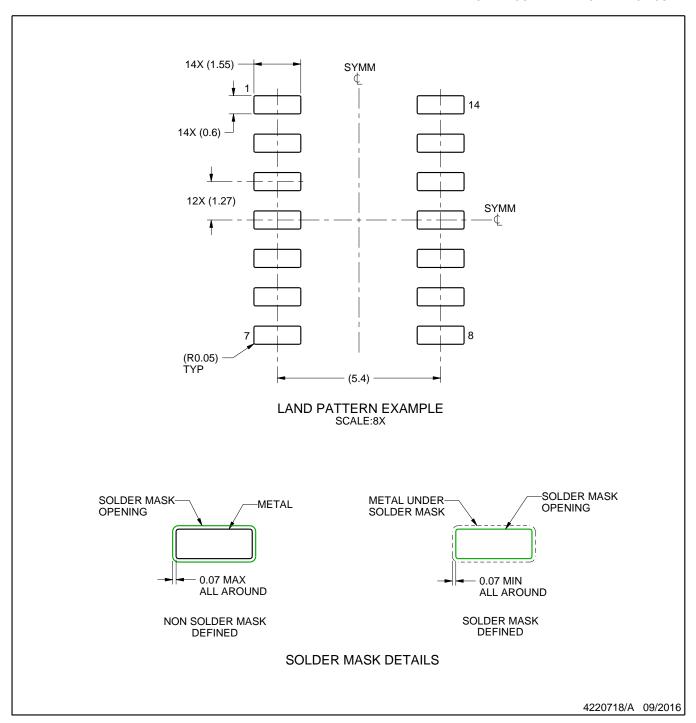
- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



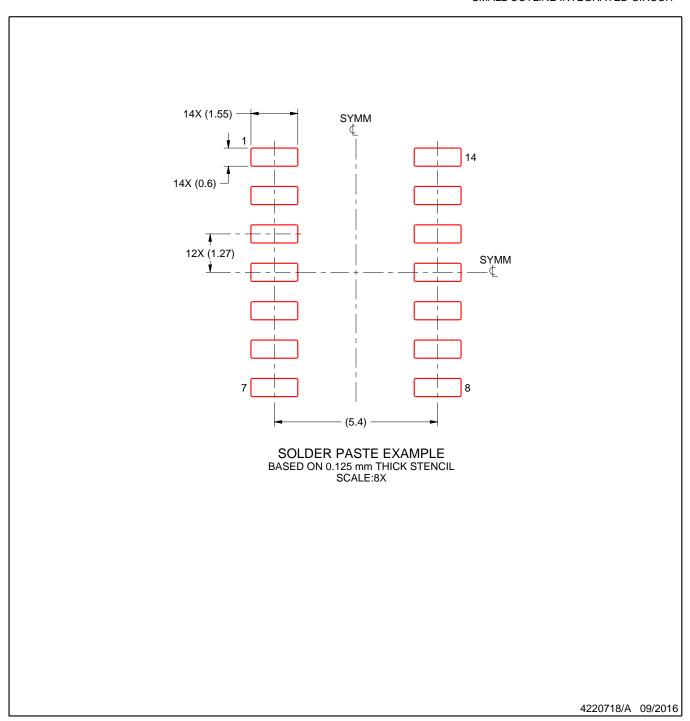
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

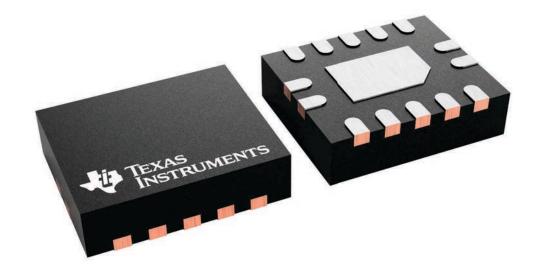
- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



2.5 x 3, 0.5 mm pitch

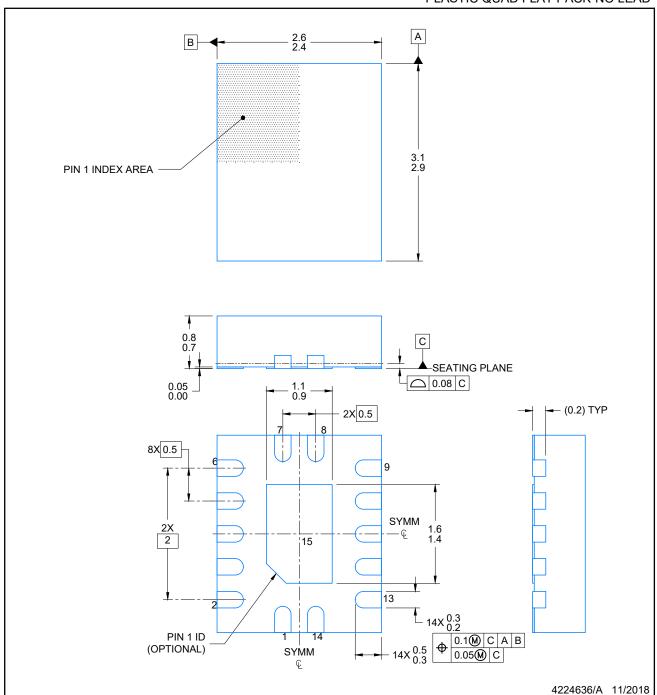
PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC QUAD FLAT PACK-NO LEAD

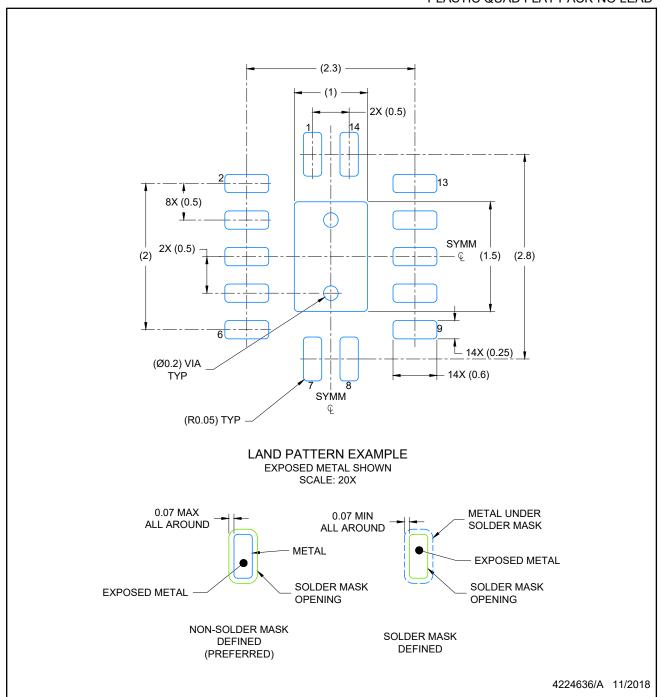


#### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUAD FLAT PACK-NO LEAD

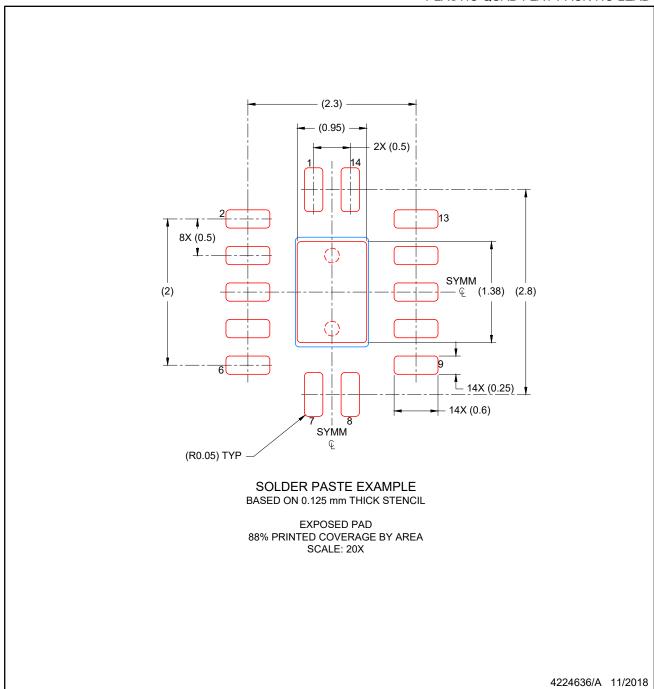


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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